Notice of References Cited

Application/Control No. 10/005,573	Applicant(s)/i Reexamination VIAUD, JEAN	on
Examiner	Art Unit	
Brian I Albertalli	2655	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,131,061 A	10-2000	DenBraber et al.	701/50
*	В	US-5,704,008	12-1997	Duvall, Jr., William Robert	704/273
*	С	US-2002/0150267	10-2002	Furuta, Hideto	381/110
*	D	US-2002/0152079	10-2002	Furuta, Hideto	704/275
*	E	US-5,774,858	06-1998	Taubkin et al.	704/273
*	F	US-5,524,368	06-1996	Struck et al.	37/235
	G	US-			
	Η	US-			
	ı	US-	,		
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2000-056827	02-2000	Japan	Fujioka	G05D 1/00
	0	JP07187562	07-1995	Japan	Maeda	B66C 13/40
	Р	JP360120411	07-1985	Japan	Nonaka et al.	G05B 24/02
	Q	,				
	R	-				
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	Х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.